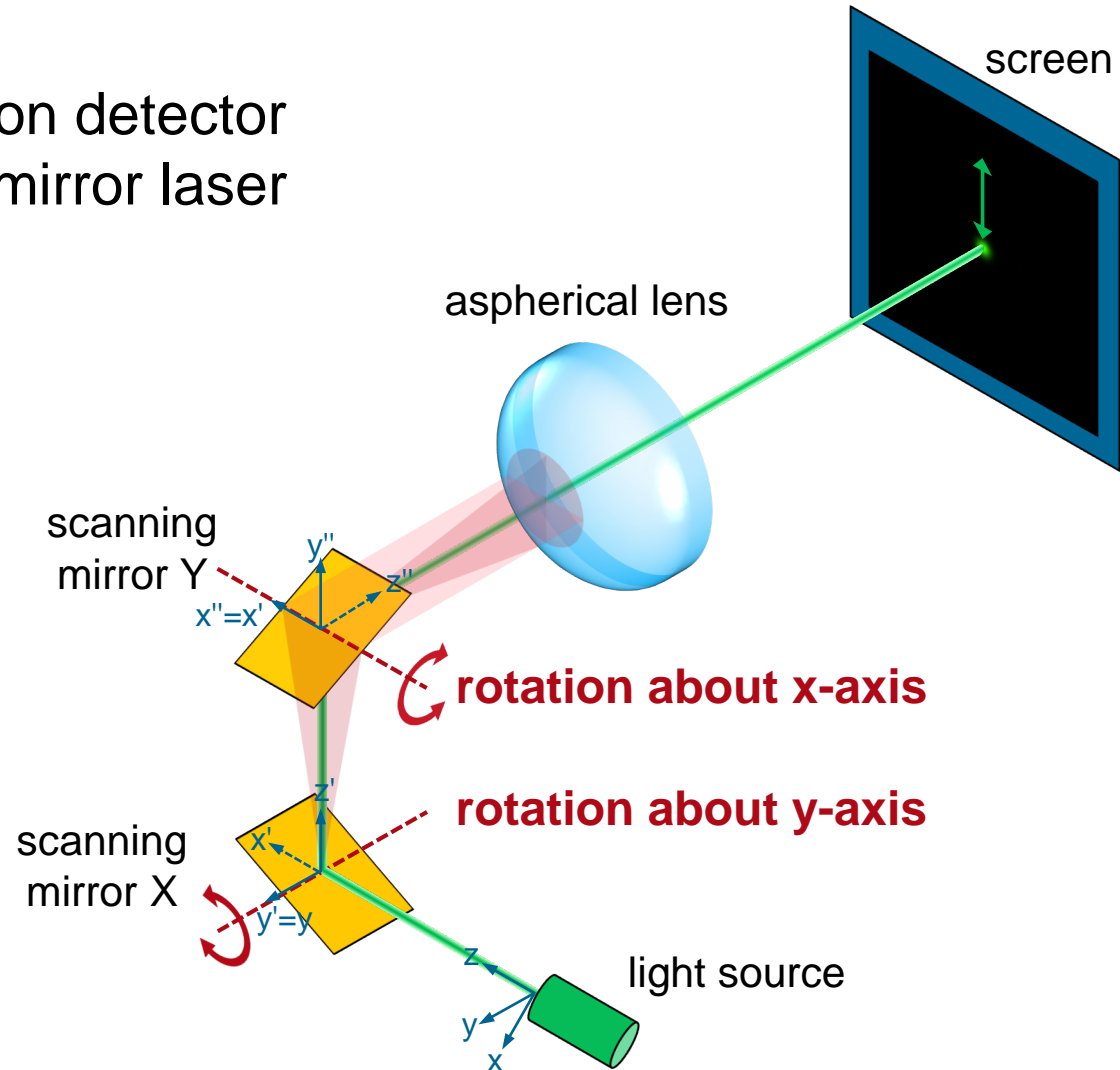


Laser Systems > Scanning Systems

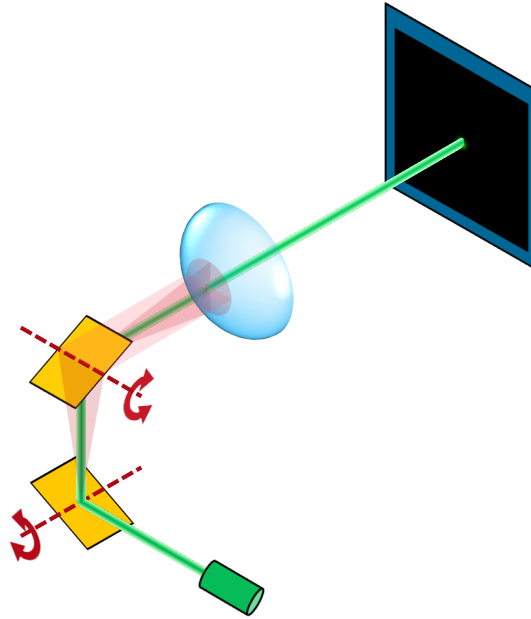
# **Performance Analysis of Laser Scanning System Using an Asphere**

# Task/System Illustration

Simulation of spots on detector deflected by a dual mirror laser scanning system.

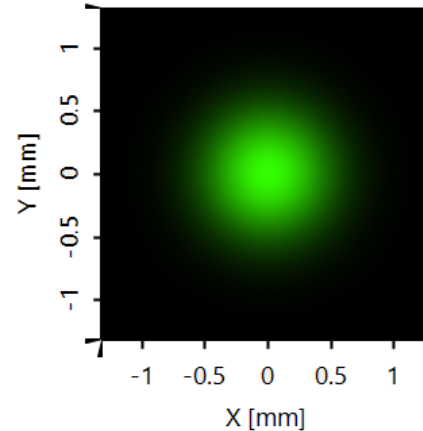
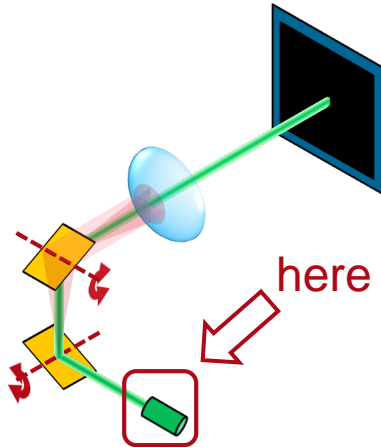


# Highlights



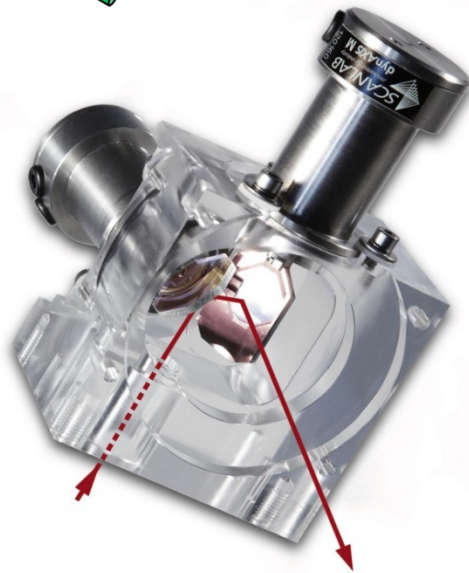
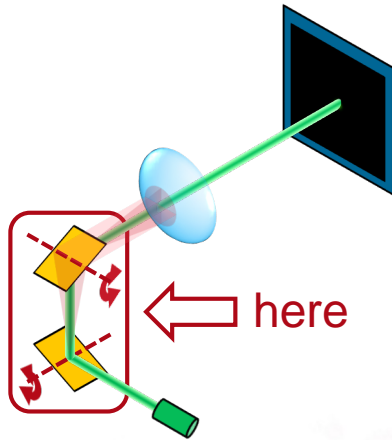
- modeling of user-defined scanning processes
- variety of selectable angle definitions
- fast simulation through full scanning and additional optical setup
- evaluation of distortion of scanned spots

# Specification: Light Source



Parameter	Description / Value & Unit
model/number	single mode laser from Laser Components: FP-D-532-1-C-F
coherence/mode	single Hermite Gaussian (0,0) mode
wavelength	532nm
polarization	linear in x-direction (0°)
half angle divergence of beam intensity	0.02°×0.02° (referring to 1/e <sup>2</sup> )
initial M <sup>2</sup>	1.0 × 1.0

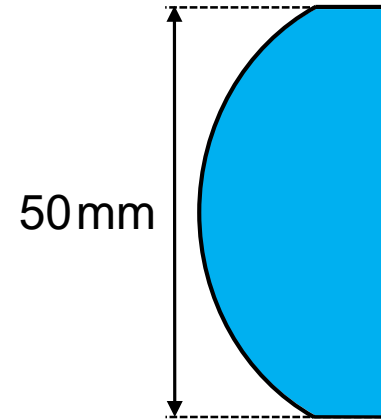
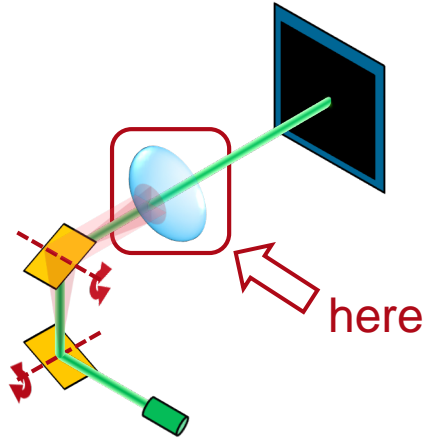
# Specification: Galvanometer Mirror System



Typical dual axis galvanometer scanner [1]

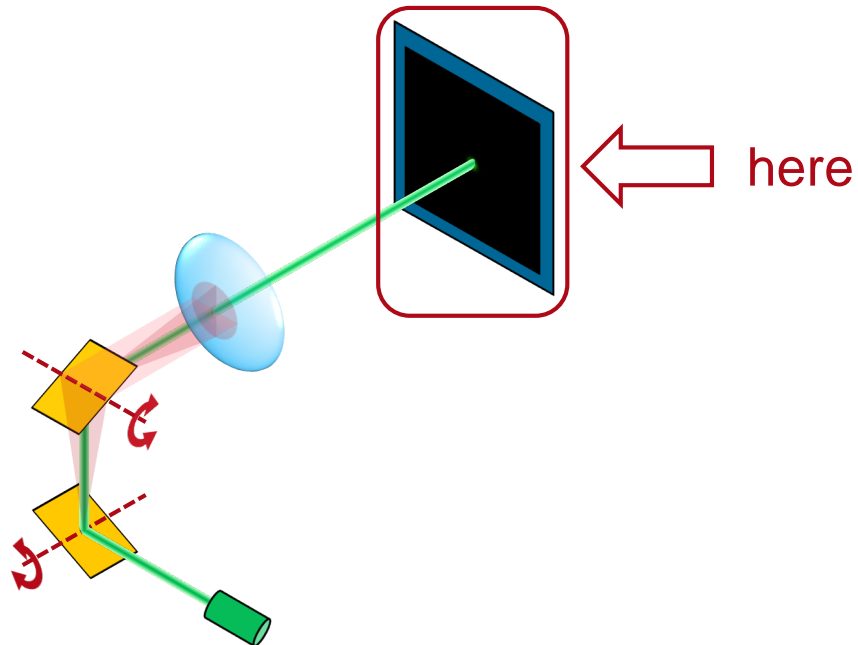
Parameter	Value & Unit
type/model	dual-axis mirror assembly from Thorlabs: GVS002
mechanical scan angle	$\pm 12.5^\circ$
optical scan angle	$\pm 25^\circ$

# Specification: Asphere as Scanning Optics



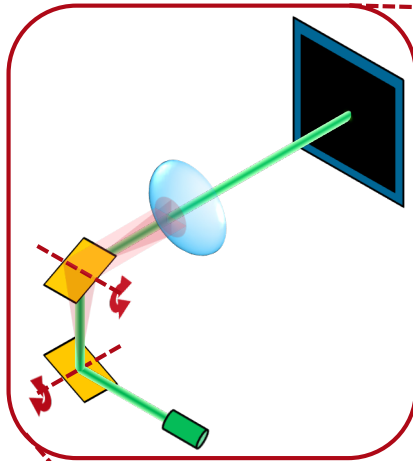
Parameter	Value & Unit
type	convex-plano aspherical lens
model	Asphericon ALL50-100-S-U (A50-100LPX)
numerical aperture (NA)	0.23
material	N-BK7

# Specification: Detectors



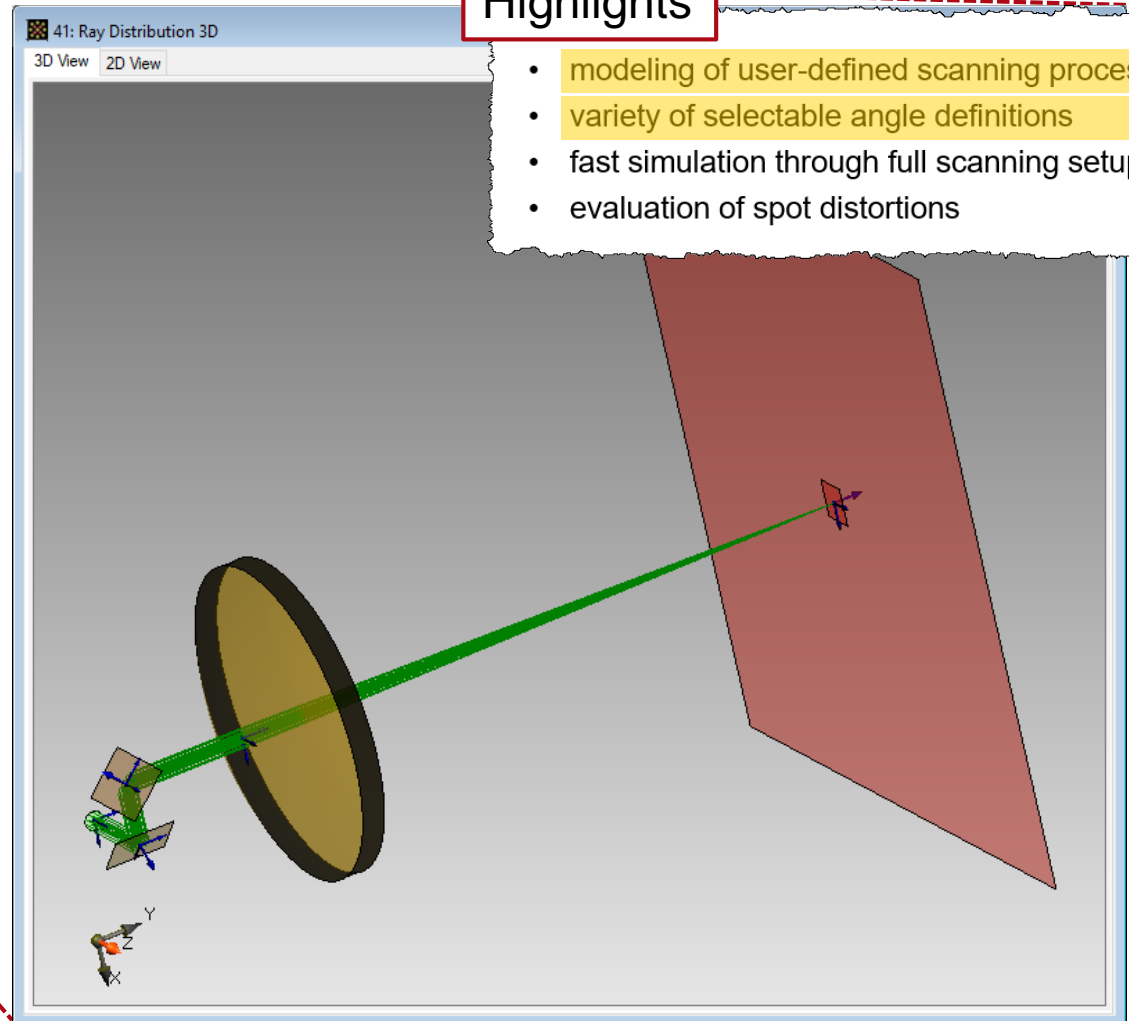
Position	Modeling Technique	Detector/Analyzers
full system	3D system ray tracing	3D illustration of system and ray propagation
target region	ray tracing	focal position
target region	field tracing	shape, size & quality of target spots

# Result: 3D System Ray Tracing



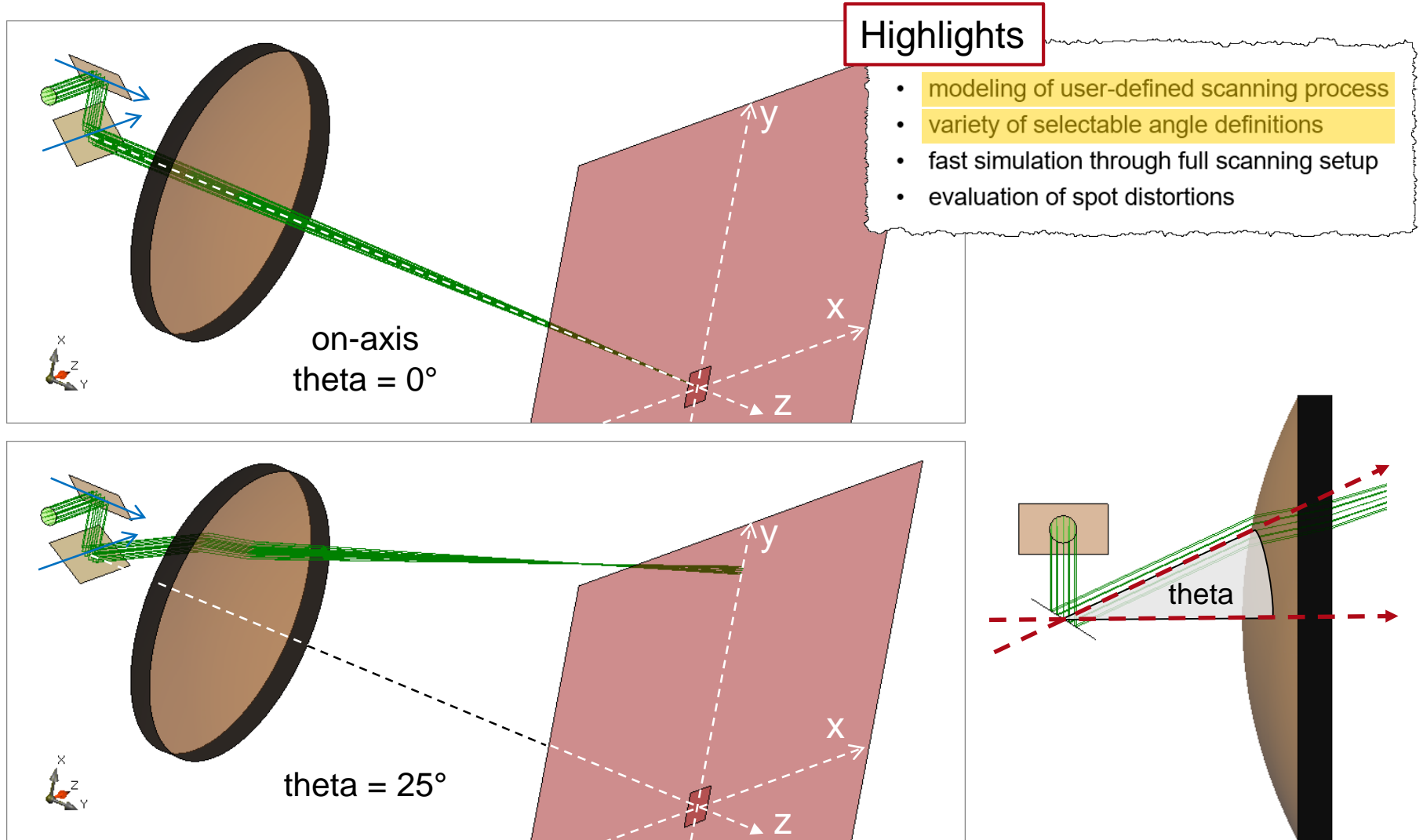
## Highlights

- modeling of user-defined scanning process
- variety of selectable angle definitions
- fast simulation through full scanning setup
- evaluation of spot distortions

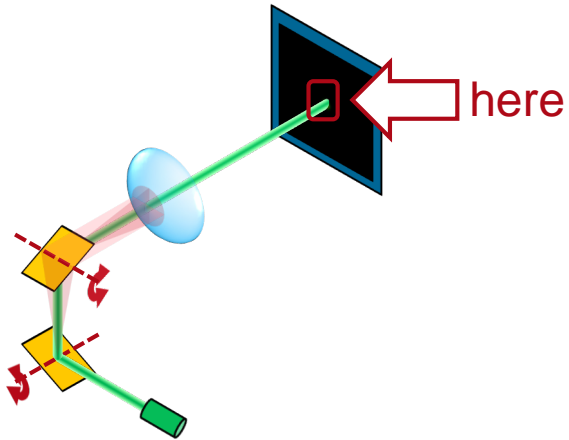




# Results: 3D Ray Tracing (On- & Off-Axis)

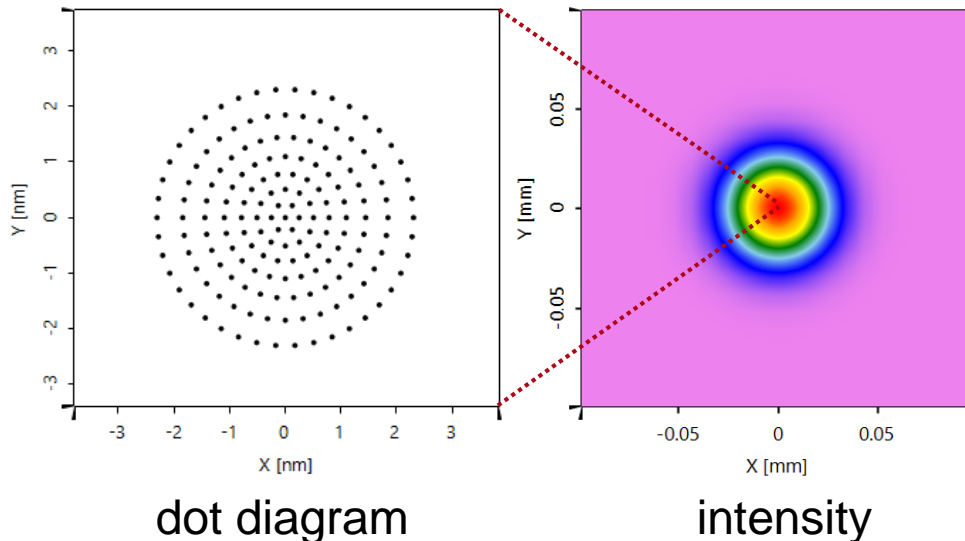


# Results: Beam Profile On-Axis



## Highlights

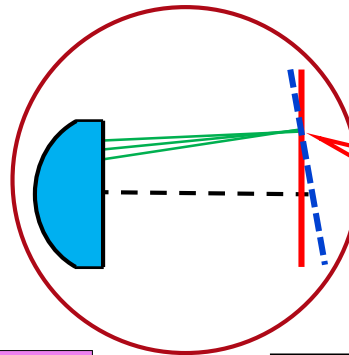
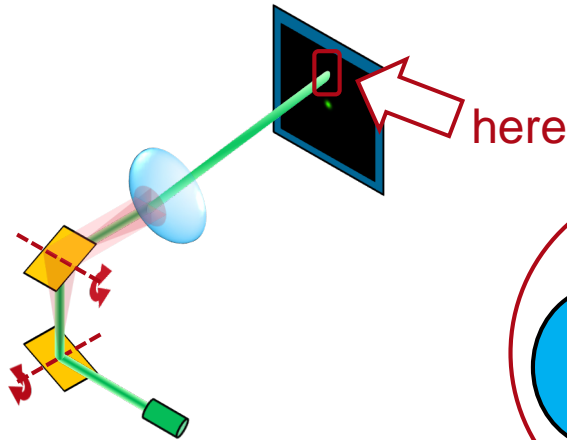
- modeling of user-defined scanning process
- variety of selectable angle definitions
- fast simulation through full scanning setup
- evaluation of spot distortions



Parameters	Values / $\mu\text{m}$
RMS beam diameter (x × y) by ray tracing	0 $\mu\text{m}$ × 0 $\mu\text{m}$ below diffraction limit
focus spot 1/e <sup>2</sup> diameter (x × y) by field tracing	69 $\mu\text{m}$ × 69 $\mu\text{m}$
M <sup>2</sup> value (x × y) by field tracing	1.00 × 1.00

**simulation time:  
~4s !!!**

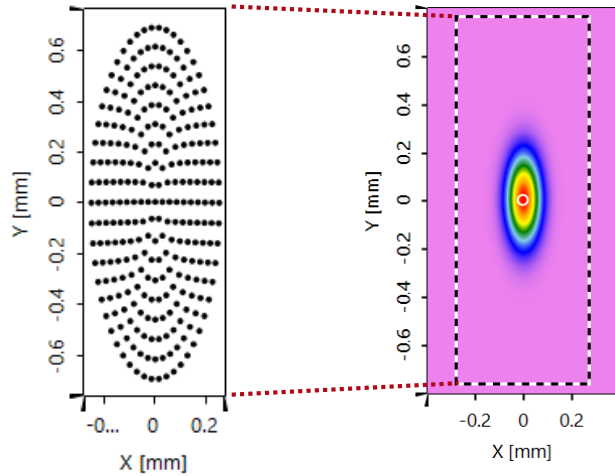
# Results: Beam Profile Off-Axis



detector plane normal to optical axis (not tilted)

## Highlights

- modeling of user-defined scanning process
- variety of selectable angle definitions
- fast simulation through full scanning setup
- evaluation of spot distortions



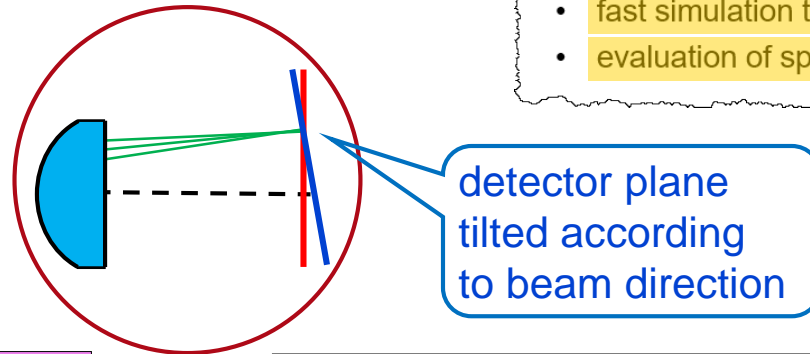
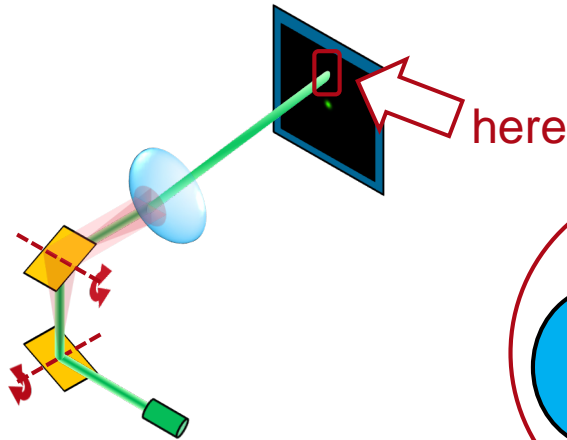
dot diagram

intensity

Parameters	Values / $\mu\text{m}$
RMS beam diameter (x x y) by ray tracing	265 $\mu\text{m}$ x 729 $\mu\text{m}$ can't consider intensity modulation
focus spot 1/e <sup>2</sup> diameter (x x y) by field tracing	179 $\mu\text{m}$ x 465 $\mu\text{m}$
M <sup>2</sup> value (x x y) by field tracing	1.00 x 1.13

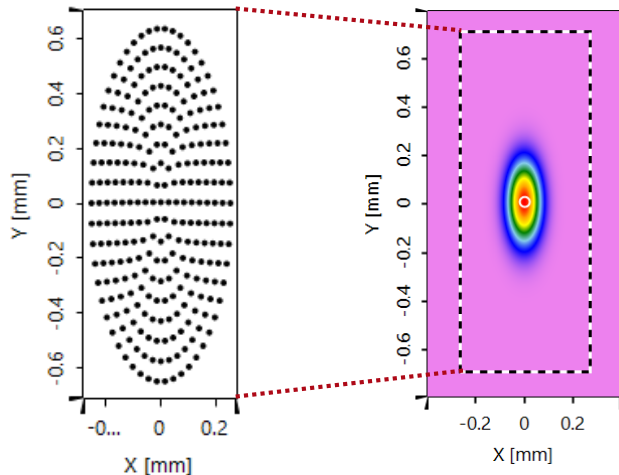
**simulation time:  
~5s !!!**

# Results: Beam Profile Off-Axis (Tilted Detector)



## Highlights

- modeling of user-defined scanning process
- variety of selectable angle definitions
- fast simulation through full scanning setup
- evaluation of spot distortions



dot diagram

intensity

## Parameters

RMS beam diameter  
(x × y) by ray tracing

## Values / $\mu\text{m}$

265  $\mu\text{m}$  × 677  $\mu\text{m}$   
can't consider intensity modulation

focus spot 1/e<sup>2</sup> diameter  
(x × y) by field tracing

179  $\mu\text{m}$  × 432  $\mu\text{m}$

M<sup>2</sup> value (x × y) by field tracing

1.00 × 1.05

**simulation time:  
~5s !!!**

# Results: Scan Process

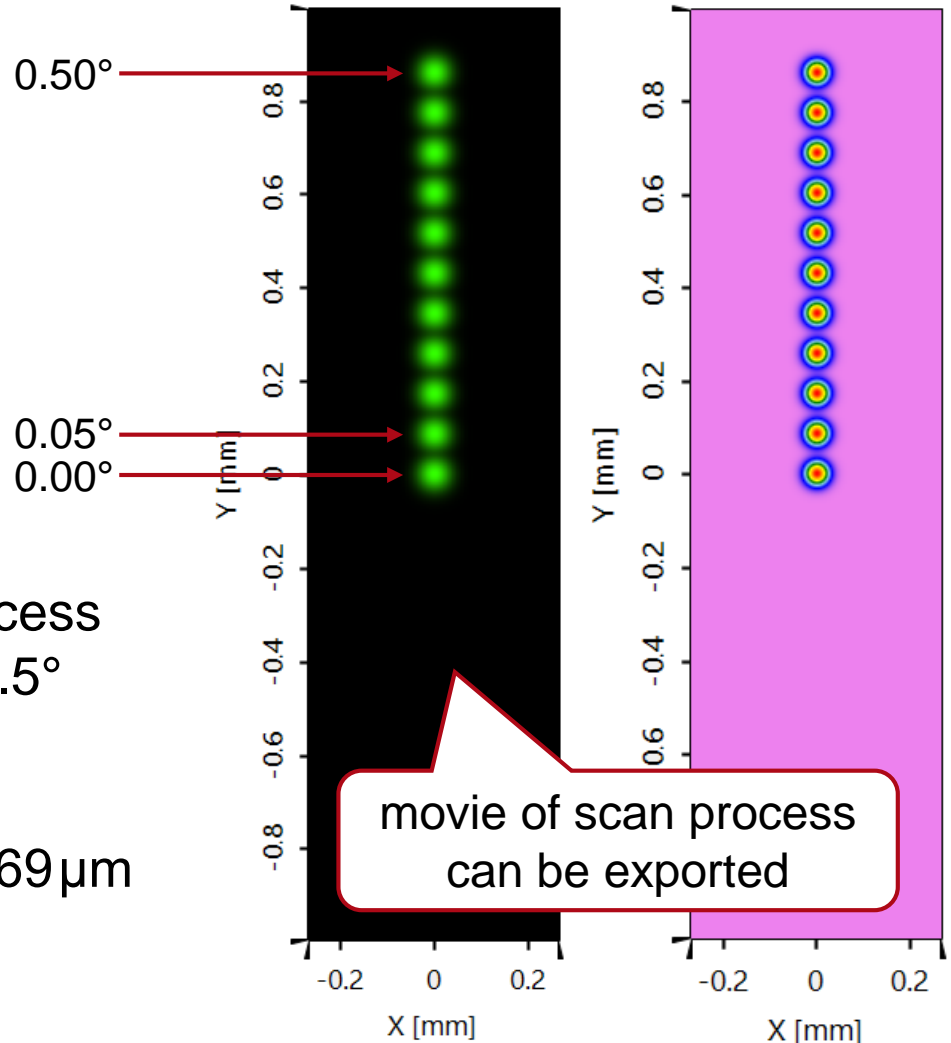
## Highlights

- modeling of user-defined scanning process
- variety of selectable angle definitions
- fast simulation through full scanning setup
- evaluation of spot distortions

illustrated simulation of scan process  
for deflection angles from  $0^\circ$  to  $0.5^\circ$

$1/e^2$  diameter of paraxial spots  $\sim 69\mu\text{m}$

**simulation time:  
~7s !!!**



# Document & Technical Info

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code	SS.0001
version of document	1.0
title	Performance Analysis of Laser Scanning System Using an Aspherical Lens
category	Laser Systems > Scanning Systems (SS)
author	Roberto Knoth, Hartwig Crailsheim (both LightTrans)
used VL version	7.0.0.29

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## Specifications of PC Used for Simulation

Processor	i7-4910MQ (4 CPU cores)
RAM	32GB
Operating System	Windows 10